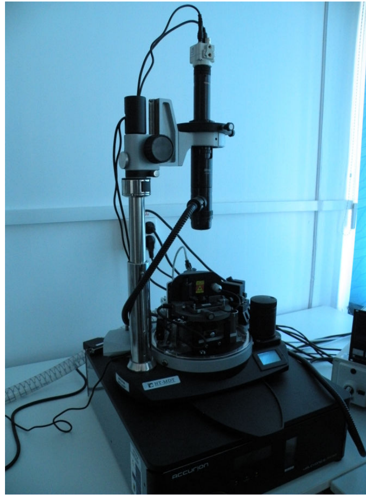
Ntegra Aura Scanning Probe Microscopy (SPM) Station



Manufacturer: NTI Co., Zelenograd, Moscow, Russia

Available techniques:

1. Atomic Force Microscopy (AFM) with:
   - (Contact mode) Force modulation technique. Topography and local elasticity images.
   - (Contact mode) Contact Capacitance Technique. Topography and local capacitance images.
   - (Contact mode) Lateral force imaging.
   - (Contact mode) Piezo Force Microscopy.
   - (Contact mode) Spreading resistance imaging.
   - (Semicontact mode) Phase contrast imaging.
   - Lithography operations. Two ways for lithography impact (BV/SP). Two ways for lithography execution (Raster/Vector).
   - Heating stage operations.
   - Operations in liquid.
2. Double-pass techniques:
   - Magnetic Force Microscopy (MFM).
   - Electrostatic Force Microscopy (EFM).
   - Scanning Kelvin Microscopy (SKM).
   - Scanning Capacitance Microscopy (SCM).
3. Scanning Tunneling Microscopy (STM) mode.
4. Nanoindentation.